

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appln. No. : 10/564,197  
Applicant : F. ENDERWEIT  
Filed :  
TC/A.U. :  
Examiner :

Docket No. : 2145-156  
Customer No. : 06449  
Confirmation No. : 7453

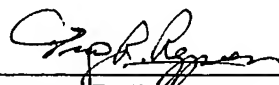
**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Director of the United States Patent  
and Trademark Office  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant submits herewith information that the Office may wish to consider in examination of the subject application. Materials submitted for consideration are listed on the attached form PTO-1449.

Respectfully submitted,

By   
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|--|---|----|---|------------------------|------------|
| <b>INFORMATION DISCLOSURE<br/>STATEMENT BY APPLICANT</b> |   |    |   | Complete if Known      |            |
|  |   |    |   | Application Number     | 10/564,197 |
|  |   |    |   | Filing Date            |            |
|  |   |    |   | First Named Inventor   | ENDERWEIT  |
|  |   |    |   | Group Art Unit         |            |
|  |   |    |   | Examiner Name          |            |
|  |   |    |   | Confirmation No.       | 7453       |
| Sheet  | 1 | of | 3 | Attorney Docket Number | 2145-156   |

| U.S. PATENT DOCUMENTS |                          |                      |                                      |  |  |
|-----------------------|--------------------------|----------------------|--------------------------------------|--|--|
| Examiner<br>Initials* | Cite<br>No. <sup>1</sup> | U.S. Patent Document |                                      | Name of Patentee or Applicant<br>of Cited Document | Date of Publication<br>of Cited Document<br>MM-DD-YYYY |
|                       |                          | Number               | Kind Code <sup>2</sup><br>(if known) |  |  |
|                       | 1                        | 7,001,065            | B2                                   | DISHAW et al.                                      | 02-21-2006   |
|                       | 2                        | 2004/099553          | A2                                   | ECKEL  | 11-18-2004   |
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code. <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.

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|  |   |    |   | Examiner Name            |            |
|  |   |    |   | Confirmation No.         | 7453       |
| Sheet  | 2 | of | 3 | Attorney Docket Number   | 2145-156   |

| FOREIGN PATENT DOCUMENTS |                          |                             |                     |                                 |  |  |                |
|--------------------------|--------------------------|-----------------------------|---------------------|---------------------------------|--|--|----------------|
| Examiner<br>Initials*    | Cite<br>No. <sup>1</sup> | Foreign Patent Document     |                     |                                 | Name of Patentee or Applicant<br>of Cited Document | Date of Publication<br>of Cited Document<br>MM-DD-YYYY | T <sup>6</sup> |
|                          |                          | Office <sup>3</sup><br>Code | Number <sup>4</sup> | Kind <sup>5</sup><br>(if known) |  |  |                |
|                          | 3                        | JP                          | 56-153228           |                                 | Nippon Electron Optics<br>Lab                      | 11-27-1981   | AB             |
|                          | 4                        | JP                          | 1981-153228         |                                 | JEOL Corporation                                   | 11-27-1981   | ✓              |
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| Examiner<br>Signature    |                          |                             |                     |                                 | Date<br>Considered                                 |  |                |

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| Sheet  | 3 | of | 3 | Attorney Docket Number   | 2145-156   |

| NON PATENT LITERATURE DOCUMENTS |                          |  |                    |
|---------------------------------|--------------------------|--|--------------------|
| Examiner<br>Initials*           | Cite<br>No. <sup>1</sup> | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published | T <sup>2</sup>     |
|                                 | 5                        | <i>THERMACAM PM 695: High Performance Handheld Thermal Imaging System, The Total Predictive Maintenance Solution, FLIR Systems, 4 pages, 2000</i>  |                    |
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